

**Notice of References Cited**

Application/Control No.

09/360,069

Applicant(s)/Patent Under  
Reexamination  
WOHL ET AL.

Examiner

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Art Unit

2123

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,696,771	12-1997	Beausang et al.	714/726
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	CRC Handbook of Mathematical Sciences, 5th Edition, William H. Beyer, CRC Press, Inc., Fourth Printing, 1985, ISBN 0-8493-0655-8, page 47.
	V	Tutorial and Survey Paper: Gate-Level Test Generation for Sequential Circuits by Kwang-Ting Cheng, ACM Transactions on Design Automation of Electronic Systems, Vol. 1, No. 4, October 1996, Pages 405-442.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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